Thunderbolt over Type-C Overcoming Test Challenges

June, 2016





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Agenda

- Thunderbolt 3 Overview
- Measurement Challenges
- Tx Testing Solution
- Return Loss Testing
- Power Delivery Testing
- Rx Testing Solution
- Summary



What is Thunderbolt?

- Thunderbolt features two bidirectional (full duplex) channels that run up to 20Gbps each and allows daisy-chaining of up to six devices.
- Passive or active Cable
- Thunderbolt tunnels two protocols (PCI Express and DisplayPort) when running in native Thunderbolt mode.



Evolution of Thunderbolt



Thunderbolt 3 Overview

- Announced in Q2 2015
- Uses the Type-C connector
- Channel aggregation: two independent 20Gbps links into one logical 40Gbps link
- Supports other standards through ALT mode
- Cost competitive vs multi-chip, discrete, mux solutions



More Speed

- 40Gb/s Thunderbolt™ 3
 - Bi-directional, PCI Express and DisplayPort
 - Four lanes of PCI Express Gen 3
 - Eight lanes of DisplayPort 1.2
- Native USB 3.1 (up to 10Gb/s)
- Native DisplayPort 1.2





More Possibilities



4K Video



Single-cable docking with charging



External graphics



Thunderbolt[™] networking



Configurations

- Daisy-chain up to six devices if the link is in Thunderbolt mode
- Second device port operates the same as computer port and supports Thunderbolt, USB, and DisplayPort devices





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Testing Methodology

- PHY testing approach will be similar to Thunderbolt 2

- Tx, Rx, and Return Loss
- PD for Type-C Alternate Mode
- DP, USB for Type-C

- Keysight can help with pre-compliance testing

Thunderbolt[™] Interconnect Specification

USB Type-C Thunderbolt Alternate Mode USB Type-C Thunderbolt Alternate Mode Electrical Host \ Device Compliance Test Specification





















Type-C Design and Test Challenges: Overview





USB 3.1 TX Compliance Application





Simulation-Measurement Correlation Challenge Simulation...











Simulation Test Solutions: Advanced Design System



Type-C Revolution

Physical Layer Testing: High speed data lanes





Thunderbolt over Type-C Overcoming Test Challenges

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Oscilloscope



Physical Layer Testing: High speed data lanes

Transmitter Testpoints

Standard	TP2	ТР3	TP3Eq	Comments
USB3.1compliance USB3.1 pre-comp	х	х	Y Y	USB3.1 has various fixtures One connection testing. Test Mode signal compliance patterns
TBT3	X			PRBS31 is effectively random data signal.
DP1.4	х		Y	D10.2, PRBS7, HBR2CPAT
MHL3.3	х		Y	BIST randomized PRBS

Acquisition

Each Standard has its own suite of tests each with their own particular measurement processes.



Tx: Compliance Test Overview: USB 3.1, MHL, DP, TB

Image: BETA VERSION 2.01.9044) USB3.1 USB3 Device 1	×
Task Flow _ Set Up Select Tests Configure Connect Run Tests Automation Results Html Report	1
Set Up	
E → O SG Test	
↓ □ ○ 5G Transmitter SSC Tests	
Select Task	
Bin O 5G Transmitter Eye Far End (TP 1) Tests (USB-IF SigTest)(CTLE On)	
B → 0 JUG Iransmitter Low Frequency Penodic Signaling Tests	
Configure B	
P	- 11
E □ □ 0 10G deemphasis and preshoot test	- 11
	- 11
Connect	- 1
(Click a test's name to see description)	-1
Cuck a test's name to see description/	
Kuintests	
	~
Limit Set: USB 3.1 Specification Version 1.0	
	Ψ.
✓ 0 Tests Check the test(s) you would like to run Connection: UNKNOWN	

- Multiple Compliance Applications Releasing into the Type-C Eco-System
- USB 3.1 <u>U7243B</u>
- DP 1.3 <u>U7232D</u>
- Thunderbolt <u>N6463B</u>
- MHL 3.3 <u>N6460B</u>
- USB PD <u>N8840A</u>

An Entire Eco-System Enabled



Tx: Compliance Test Overview: New High Speed Fixture

- Highest signal integrity Type-C test fixture
- Type-C plug interface fixture handling connector "flip"
- Compliance test capability for USB 3.1, DisplayPort 1.3, Thunderbolt 2/3, MHL
- Best signal integrity: 20 GHz bandwidth (at -3 dB), de-embeddable up to 30 GHz
- Provides test point and probing access for transmitter and power delivery measurements
- Provides the elements to seamlessly leverage Keysight's portfolio of compliance test applications







Tx: Special Decoders and Triggers for the Type-C Ecosystem



USB Power Delivery Decode

- Industry's only hardware based triggering
- Time aligned decoding
- Set up the entire trigger in 30 seconds
- Quickly scan through numerous events

USB 3.1 Decode

- Industry's only USB 3.1 decoder
- Time aligned decoding
- Quickly scan through numerous events



Physical Layer Testing: High speed data lane control

Standard/ Device	Needed for Control of device under test
All	Power Delivery Controller is required to set V _{Bus} setting, current or charge level if any, consumer or provider and to initiate alternate modes.
USB3.1TX	Compliance Mode by termination and LFPS ping, LBPM testing by LBPM initial simulation. HSETT for Hosts/Hubs
USB3.1 RX	Link Training Simulation through discovery and equalization processes to get into loopback.
ТВТ	TenLira SW from Intel to set up patterns and data rates
DP1.4 TX	Type C to DP adapter, DP Reference Sink, DPCD test modes active
DP1.4 RX	Type C to DP adapter, DP Reference Source, DPCD error counting active
MHL3.3	eCbus Controller and fixtures



Thunderbolt 3 Transmitter Test

- 25GHz BW required for compliance testing, more if closer to the silicon
- Thunderbolt-specific SW (Imaginarium, TenLira, TCL, scripts)
- Crosstalk generator
- Type-C test fixture
- UI, SSC, Rise/Fall, Jitter, Eye Diagram Near End/Far End
- New Preset testing and optimization for 10.3G and 20.6G



Thunderbolt TX and RX testing setup





Type-C Design and Test Challenges: Overview





- Significant loss at higher frequencies require more rigorous approach to removing fixture effects, to measure the true performance of the device
- Channel response affected by many features in channel (loss, reflection, crosstalk, mode conversion)
- Managing EMI and RFI levels from the cable assembly







ENA-TDR Enhanced Time Domain Analysis Option with ECal Module (N4433A)





- Significant loss at higher frequencies require more rigorous approach to removing fixture effects
 - > 2x thru de-embedding, or TRL calibration
- Channel response affected by many features in channel (loss, reflection, crosstalk, mode conversion)
 - Paradigm shift from traditional parametric testing to stressed eye testing (Channel Metrics/Margin)
- Managing EMI and RFI levels from the cable assembly
 - Cable Shielding Effectiveness





•ENA Mainframe

- •E5071C-4D5: 4-port, 300 kHz to 14 GHz
- •E5071C-4K5: 4-port, 300 kHz to 20 GHz
- •Enhanced Time Domain Analysis Option (E5071C-TDR)
- •ECal Module (N4433A)

(*) The list above includes the major equipment required. Please contact our local sales representative for configuration details.

Implementation) Step-by-step procedure on how to measure the specified parameters in the specification document using ENA Option TDR.

•Method of Implementation (MOI) document and instrument setup file will be made available for download on Keysight.com Test Fixtures Fixtures are available for purchase through Luxshare-ICT. http://web.luxshare-ict.com/en/



ENA Option TDR is a authorized test tool for Cable PHY. http://www.vesa.org/displayport-developer/certified-components/



- DUT output PRBS31 on all lanes with SSC turned on
- Setup the Network Analyzer with automated measurements specific to Thunderbolt 3





5.2 - 7 GHz

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Type-C Design and Test Challenges: Overview







KEYSIGHT TECHNOLOGIES

Receiver Testing: High speed data lanes



Receiver Testing: High speed data lanes



<u>Calibration</u>: acquisition and mathematical processing for Equalization and Eye measurement to meet <u>impaired eye</u> requirement.



Receiver Testing: High speed data lanes

Standard	CTLE	DFE	BER Method	Comments
USB3.1	х	х	Loopback	Requires sophisticated protocol aware pattern generator to go through the link training process
TBT3			Internal	PRBS31
DP1.4	х	х	Internal	HBR2CPAT (2520 bit pattern)
MHL3.3	Х		Internal	BIST randomized PRBS

Each Standard has its own 'cocktail' of jitter components and level settings to create the impaired eye. These components of jitter are measured by oscilloscope during calibration process. **M8020A JBERT**







Challenges



Thunderbolt - Jitter Impairment Calibration for RX testing

Host / Devic	e 10G & 20G			
	Inner eye	Random	Periodic	
	Voltage	Jitter	Jitter	Total Jitter
Test Case	(mV peak)	(UI pp)	(UI pp)	(UI pp)
1	350	0.14	0.17	0.38
2	35	0.14	0.17	0.66

Note:

- The device should be tested by injecting several different periodic jitter components, one at a time. The test should include at least the following sinusoidal jitter frequencies: 1MHz, 2 MHz, 10 MHz, 50MHz, and 100MHz.
- 2. AC common-mode noise should be added at the pattern-generator for ensuring worst-case transmitter characteristics. The total common-mode noise should be 100mV peak-to-peak, where the added noise profile shall be sine-wave at frequency not smaller than 400MHz.



Thunderbolt – Test Cases and Calibration Points





Receiver Testing: USB RX Test-Loopback



The DUT must brought through the whole link training state machine in order to get to the loopback state.



Receiver Testing: USB3.1 Loopback Training tool



- USB Link Training Suite is a trainings sequence generation tool for USB3.1 Gen1/2
- Easy manipulation of
 - SCD1/SCD2/LBPM
 cycles
 - TSEQ count
 - TS1 count
 - TS2 count
- LFPS parameters adjustment:
 - tPeriod, tBurst, tRepeat, tPWM....
- Choice of:
 - Power On sequence
 - Warm Reset sequence



Thunderbolt System and testpoints



The active cable provides a very robust channel which doesn't need any kind of link training (unlike PCIe 3 for example). Therefore Rx and Tx physical layer compliance test is rather simple and straight forward.



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N7016A Type-C low speed signal access and control fixture

- -Access to CC_1 , CC_2 , SBU1, SBU2, V_{BUS} and GND
- •Controls to terminate CC1, CC2 independently (R_A , R_P , R_D)
- -Control to load $V_{\mbox{CONN}}$
- •External power for power consumers
- •Type C receptacle to plug into other devices or cables (Port 2)
- •USB2.0 interface for external control from application or standalone SW on a PC









N8837A USB-PD Protocol Trigger and Decode

- Support for the USB-PD CC 4b/5b BMC encoded protocol.
- On-screen serial decode synchronized with the serial waveform
- 4b, 5b or Label display formats
- Unique listing-window view of data transfer information with an automatic click and zoom and column sort.
- Serial packet search with navigation controls
- Software trigger on search for orders Sets, Control Packets, Data Packets, and Errors.





Power Delivery: Physical Layer Compliance Test

- Keysight Infiniium S-Series Oscilloscope
 - N2873A Standard Passive Probes for CC and VBUS
- 1147B Current Probe for Load Current
- GRL-USB-PD Power Delivery SW
- USB-PD Coupon(s) from Wilder-Tech or Luxshare-ICT (USB3.1-C-PDC or TF21-215G USB-PD Coupon)
- GRL-USB-PD-C1 Controller
- Keysight Power Supply and Load











http://literature.cdn.keysight.com/litweb/pdf/5992-1463EN.pdf





Power Delivery: Physical Layer Compliance Test Chapter 5

BMC PHY





Power Role Swap







Power Delivery: Power Supply Profile Test

Chapter 7

Chapter 7: Power Supply

- Depending on Power Profile 1-5
- Source or Load Requirements
- Considering explicit Watts and Voltage







Power Solutions for Type-C PD

Choose from these instruments that meet the requirements



- Sourcing and Loading

N6752A high performance DC source module and N3303A DC electronic load module meet stringent combination of requirements for slew rate, transient response and power demands of USB PD 2.0 validation testing

- Most ordinary power products do not meet the necessary combination of requirements



USB-PD Power Integrity Measurements

- Supply drift
- PARD (Periodic and Random Disturbances)—noise, ripple and switching transients on power rails.
- Static and dynamic load response.
- Programmable power rail response.
- High frequency transients and noise.
- Product electrical validation at extended temperatures.





Large DC Offset—Probe Offset or DC Block





N7020A Power Rail Probe

Characteristics and Specifications: N7020A Power Rail Probe

Probe Bandwidth (-3dB)	2GHz	Y /
Attenuation Ratio	1:1	
Offset Range	± 24V	
* Input Impedance @ DC	50kΩ +/-2%	
Active Signal Range	± 850mV about offset voltage	v.
Probe Noise	10% increase to the noise of the connected osc	illoscope
Probe Type	Single-ended	
Included appropriate	N7021A—Coaxial Probe Head (qty 3) (\$175 us)	
Included accessories	N7022A –Main Cable (\$240)	
Maximum non-destructive input voltage	+/-30V (DC + peak AC)	
Output impedance	50Ω	
Cable length	N7021A Main Cable: 48" N7022A Coaxial Probe Head: 8"	
Ambient operating temperature	Probe Pod: 0 – 40°C, N7021A main cable, N7022A coaxial probe head	l: 0 – 85° C



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N8833A Crosstalk Analysis Tool

- Helps in identifying, quantifying and removal of crosstalk for analysis.
- Analyze up to four signals at once
- Identify the aggressor(s)
- Identify the victim
- NEXT and FEXT
- Power supply analysis (aggressor and victim)





USB-PD Test Solutions Overview

- N7020A PD Probe
- N7016A PD Test Fixture
- N8837A PD Decode SW
- N8833A Crosstalk Analysis SW
- Portfolio of Power Sources and Loads
- GRL USB-PD PHY Compliance Solution



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Your Type C device is USB3.1 Gen2 enabled and has a DP TX alt mode (4 lane) and will be a power provider at 18W profile

You will need to address:

Standard	Protocol	Phy Layer	
USBPD2	Х	X (PD Comm on cc1 and cc2, for Vbus)	I and V
USB2.0	Х	X (RX & TX)	
USB3.1	Х	X (HSD: RX & TX)	
DP1.4	Х	X (HSD: TX)/AUX Channel	×



Product Under Te

Example Device: Getting Started

First step.....Signal Observation, Access and Control.

- Consider test fixtures N7015A, N7016 and the flexibility they bring.
- Phase matched cables. Adapters etc.
- Acquire various link partners





CC1/2 V_{Bus}

Example Device: Power Delivery





Overcoming Test Challenges



Example Device: DisplayPort TX





Keysight DisplayPort1.3 Solutions





Type-C -Overcoming Test Challenges

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Thunderbolt 3 – Total Solution



KEYSIGHT TECHNOLOGIES

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Overcoming Test Challenges

Keysight USB 3.1/DP Test Solution

Design Simulation, USB-PD, and Channel Characterization





Advantages of Keysight Solution

- Keysight is the only vendor approved for Tx, Rx as well as Return Loss Testing
- Compliance Test Specification conformant test setup, characterization and test
- Simple, repeatable automated and unattended calibration and test execution using automation SW for Tx and Rx Test
- All Type-C PHY standards are addressed by Keysight's Test platform
 - Thunderbolt
 - USB
 - DisplayPort
- Keysight can help with pre-compliance testing



Questions?





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